

**IN THE UNITED STATES PATENT & TRADEMARK OFFICE**

Applicants:	CHANG et al.	Docket No.:	372465-01401 (341565)
Serial No.:	<b>10/669,496</b>	Group Art Unit:	2825
Filed:	September 23, 2003	Examiner:	Siek, Vuthe
For:	<b>METHOD FOR FASTER TIMING CLOSURE AND BETTER QUALITY OF RESULTS IN IC PHYSICAL DESIGN</b>		

Mail Stop RCE  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**REQUEST FOR CONTINUED EXAMINATION (RCE)  
UNDER 37 CFR § 1.114**

Sir:

A Request for Continued Examination (RCE) of the above-referenced application is hereby submitted.